# HEF4093B-Q100

## **Quad 2-input NAND Schmitt trigger**

Rev. 1 — 12 July 2012

**Product data sheet** 

### 1. General description

The HEF4093B-Q100 is a quad two-input NAND gate. Each input has a Schmitt trigger circuit. The gate switches at different points for positive-going and negative-going signals. The difference between the positive voltage ( $V_{T+}$ ) and the negative voltage ( $V_{T-}$ ) is defined as hysteresis voltage ( $V_H$ ).

It operates over a recommended  $V_{DD}$  power supply range of 3 V to 15 V referenced to  $V_{SS}$  (usually ground). Unused inputs must be connected to  $V_{DD}$ ,  $V_{SS}$ , or another input.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

#### 2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
  - ◆ Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Schmitt trigger input discrimination
- Fully static operation
- 5 V, 10 V, and 15 V parametric ratings
- Standardized symmetrical output characteristics
- ESD protection:
  - MIL-STD-833, method 3015 exceeds 2000 V
  - HBM JESD22-A114F exceeds 2000 V
  - MM JESD22-A115-A exceeds 200 V (C = 200 pf, R = 0 Ω)
- Complies with JEDEC standard JESD 13-B

## 3. Applications

- Wave and pulse shapers
- Astable multivibrators
- Monostable multivibrators

## 4. Ordering information

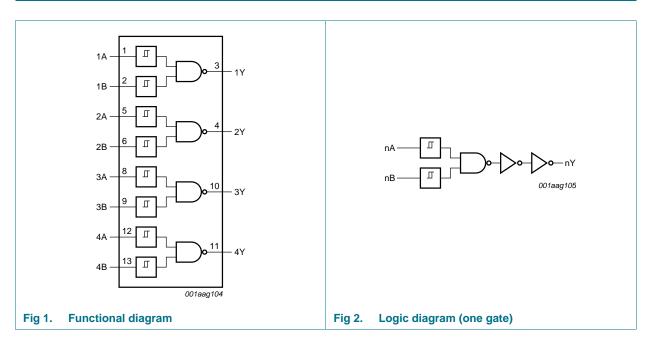
#### Table 1. Ordering information

All types operate from −40 °C to +125 °C

Type number			
	Name	Description	Version
HEF4093BT-Q100	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1

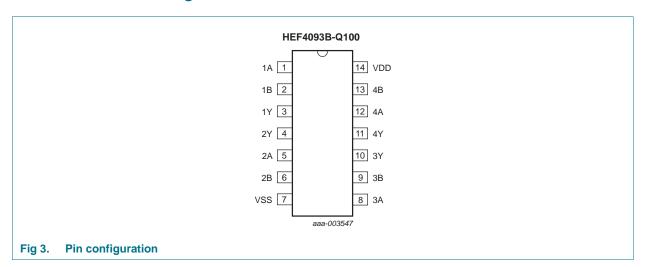


## 5. Functional diagram



### 6. Pinning information

### 6.1 Pinning



### 6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
1A to 4A	1, 5, 8, 12	input
1B to 4B	2, 6, 9, 13	input
1Y to 4Y	3, 4, 10, 11	output
$V_{DD}$	14	supply voltage
$V_{SS}$	7	ground (0 V)

## 7. Functional description

Table 3. Function table[1]

Input		Output
nA	nB	nY
L	L	н
L	Н	Н
Н	L	Н
Н	Н	L

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level.

## 8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to  $V_{SS} = 0 \text{ V}$  (ground).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DD}$	supply voltage		-0.5	+18	V
I <sub>IK</sub>	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{DD} + 0.5 \text{ V}$	-	±10	mA
VI	input voltage		-0.5	$V_{DD} + 0.5$	V
$I_{OK}$	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{DD} + 0.5 \text{ V}$	-	±10	mA
I <sub>I/O</sub>	input/output current		-	±10	mA
$I_{DD}$	supply current		-	50	mA
$T_{stg}$	storage temperature		-65	+150	°C
T <sub>amb</sub>	ambient temperature		-40	+125	°C
$P_{tot}$	total power dissipation	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C}$			
		SO14	[1] -	500	mW
Р	power dissipation	per output	-	100	mW

<sup>[1]</sup> For SO14 package: above  $T_{amb}$  = 70 °C,  $P_{tot}$  derates linearly with 8 mW/K.

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## 9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DD}$	supply voltage		3	15	V
VI	input voltage		0	$V_{DD}$	V
T <sub>amb</sub>	ambient temperature	in free air	-40	+125	°C

### 10. Static characteristics

Table 6. Static characteristics

 $V_{SS} = 0$  V;  $V_{I} = V_{SS}$  or  $V_{DD}$ ; unless otherwise specified.

Symbol	Parameter	Conditions	$V_{DD}$	T <sub>amb</sub> =	–40 °C	T <sub>amb</sub> =	+25 °C	T <sub>amb</sub> =	+85 °C	T <sub>amb</sub> = +	-125 °C	Unit	
				Min	Max	Min	Max	Min	Max	Min	Max		
$V_{OH}$	HIGH-level	$ I_{O}  < 1 \mu A$	5 V	4.95	-	4.95	-	4.95	-	4.95	-	V	
	output voltage		10 V	9.95	-	9.95	-	9.95	-	9.95	-	V	
			15 V	14.95	-	14.95	-	14.95	-	14.95	-	V	
$V_{OL}$	LOW-level	$ I_{O}  < 1 \mu A$	5 V	-	0.05	-	0.05	-	0.05	-	0.05	V	
	output voltage		10 V	-	0.05	-	0.05	-	0.05	-	0.05	V	
			15 V	-	0.05	-	0.05	-	0.05	-	0.05	V	
I <sub>OH</sub>	HIGH-level	$V_0 = 2.5 \text{ V}$	5 V	-1.7	-	-1.4	-	-1.1	-	-1.1	-	mΑ	
	output current	output current	$V_0 = 4.6 \text{ V}$	5 V	-0.64	-	-0.5	-	-0.36	-	-0.36	-	mΑ
		V <sub>O</sub> = 9.5 V	10 V	-1.6	-	-1.3	-	-0.9	-	-0.9	-	mΑ	
		V <sub>O</sub> = 13.5 V	15 V	-4.2	-	-3.4	-	-2.4	-	-2.4	-	mA	
I <sub>OL</sub>	LOW-level	$V_0 = 0.4 \ V$	5 V	0.64	-	0.5	-	0.36	-	0.36	-	mΑ	
	output current	$V_0 = 0.5 \ V$	10 V	1.6	-	1.3	-	0.9	-	0.9	-	mA	
		V <sub>O</sub> = 1.5 V	15 V	4.2	-	3.4	-	2.4	-	2.4	-	mΑ	
I <sub>I</sub>	input leakage current		15 V	-	±0.1	-	±0.1	-	±1.0	-	±1.0	μΑ	
I <sub>DD</sub>	supply current	all valid input	5 V	-	0.25	-	0.25	-	7.5	-	7.5	μΑ	
		combinations; $I_O = 0 A$	10 V	-	0.5	-	0.5	-	15.0	-	15.0	μΑ	
			15 V	-	1.0	-	1.0	-	30.0	-	30.0	μΑ	
Cı	input capacitance			-	-	-	7.5	-	-	-	-	pF	

## 11. Dynamic characteristics

Table 7. Dynamic characteristics

 $T_{amb} = 25$  °C;  $C_L = 50$  pF;  $t_r = t_f \le 20$  ns; wave forms see Figure 4; test circuit see Figure 5; unless otherwise specified.

Symbol	Parameter	Conditions	$V_{DD}$	Extrapolation formula[1]	Min	Тур	Max	Unit
t <sub>PHL</sub>	HIGH to LOW	nA or nB to nY	5 V	63 ns + $(0.55 \text{ ns/pF})C_L$	-	90	185	ns
	propagation delay		10 V	29 ns + (0.23 ns/pF)C <sub>L</sub>	-	40	80	ns
			15 V	22 ns + (0.16 ns/pF)C <sub>L</sub>	-	30	60	ns
t <sub>PLH</sub>	LOW to HIGH	nA or nB to nY	5 V	58 ns + (0.55 ns/pF)C <sub>L</sub>	-	85	170	ns
propagation delay	propagation delay		10 V	29 ns + (0.23 ns/pF)C <sub>L</sub>	-	40	80	ns
			15 V	22 ns + (0.16 ns/pF)C <sub>L</sub>	-	30	60	ns
t <sub>THL</sub>	HIGH to LOW output	nY to LOW	5 V	10 ns + (1.00 ns/pF)C <sub>L</sub>	-	60	120	ns
	transition time		10 V	9 ns + (0.42 ns/pF)C <sub>L</sub>	-	30	60	ns
			15 V	6 ns + (0.28 ns/pF)C <sub>L</sub>	-	20	40	ns
t <sub>TLH</sub>	LOW to HIGH output transition time	nA or nB to HIGH	5 V	10 ns + (1.00 ns/pF)C <sub>L</sub>	-	60	120	ns
			10 V	9 ns + (0.42 ns/pF)C <sub>L</sub>	-	30	60	ns
			15 V	6 ns + (0.28 ns/pF)C <sub>L</sub>	-	20	40	ns

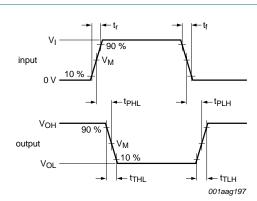
<sup>[1]</sup> Typical value of the propagation delay and output transition time can be calculated with the extrapolation formula ( $C_L$  in pF).

Table 8. Dynamic power dissipation

 $V_{SS} = 0 \ V; \ t_r = t_f \le 20 \ ns; \ T_{amb} = 25 \ ^{\circ}C.$ 

Symbol	Parameter	$V_{DD}$	Typical formula	where:
$P_D$	dynamic power	5 V	$P_D = 1300 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2 (\mu W)$	f <sub>i</sub> = input frequency in MHz;
	dissipation	dissipation $10 \text{ V}  P_D = 6400 \times 10^{-3} \text{ P}_D = 6400 \times 10^{-3} $	$P_D = 6400 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2 (\mu W)$	f <sub>o</sub> = output frequency in MHz;
	15	15 V	$P_D = 18700 \times f_i + \Sigma (f_0 \times C_L) \times V_{DD}^2 (\mu W)$	$C_L$ = output load capacitance in pF; $\Sigma(f_0 \times C_L)$ = sum of the outputs;
				$V_{DD}$ = supply voltage in V.

#### 12. Waveforms



Measurement points are given in Table 9.

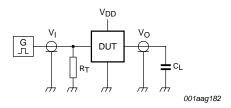
Logic levels: V<sub>OL</sub> and V<sub>OH</sub> are typical output voltage levels that occur with the output load.

 $t_r$ ,  $t_f$  = input rise and fall times.

Fig 4. Propagation delay and output transition time

Table 9. Measurement points

Supply voltage	Input	Output
$V_{DD}$	V <sub>M</sub>	V <sub>M</sub>
5 V to 15 V	0.5V <sub>DD</sub>	0.5V <sub>DD</sub>



Test data given in Table 10.

Definitions for test circuit:

DUT = Device Under Test.

 $C_L$  = load capacitance including jig and probe capacitance.

 $R_T$  = termination resistance should be equal to the output impedance  $Z_o$  of the pulse generator.

Fig 5. Test circuit

Table 10. Test data

Supply voltage	Input	Load	
$V_{DD}$	VI	t <sub>r</sub> , t <sub>f</sub>	CL
5 V to 15 V	V <sub>SS</sub> or V <sub>DD</sub>	≤ 20 ns	50 pF

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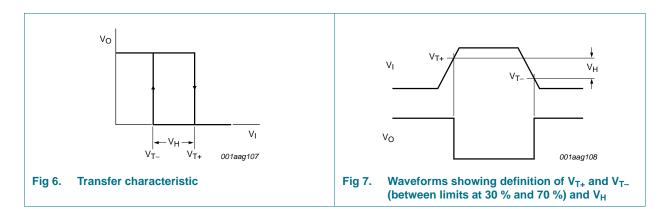
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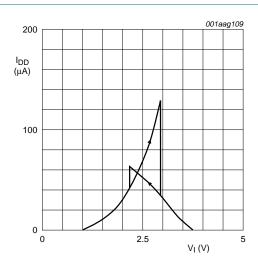
### 13. Transfer characteristics

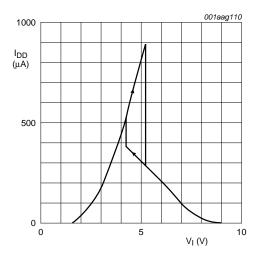
Table 11. Transfer characteristics

 $V_{SS} = 0 \text{ V}$ ;  $T_{amb} = 25 \text{ °C}$ ; see Figure 6 and Figure 7.

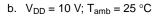
Symbol	Parameter	Conditions	$V_{\mathrm{DD}}$	Min	Тур	Max	Unit
$V_{T+}$	positive-going threshold voltage		5 V	1.9	2.9	3.5	V
			10 V	3.6	5.2	7	V
			15 V	4.7	7.3	11	V
$V_{T-}$	negative-going threshold voltage		5 V	1.5	2.2	3.1	V
			10 V	3	4.2	6.4	V
			15 V	4	6.0	10.3	V
$V_{H}$	hysteresis voltage		5 V	0.4	0.7	-	V
			10 V	0.6	1.0	-	V
			15 V	0.7	1.3	-	V

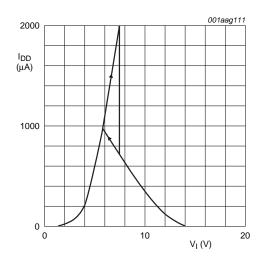






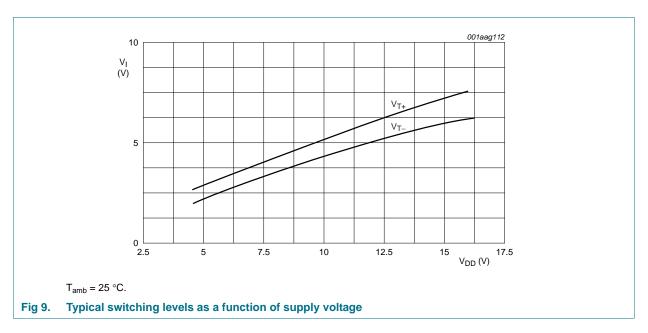
a.  $V_{DD} = 5 \text{ V}$ ;  $T_{amb} = 25 \,^{\circ}\text{C}$ 





c.  $V_{DD} = 15 \text{ V}$ ;  $T_{amb} = 25 \,^{\circ}\text{C}$ 

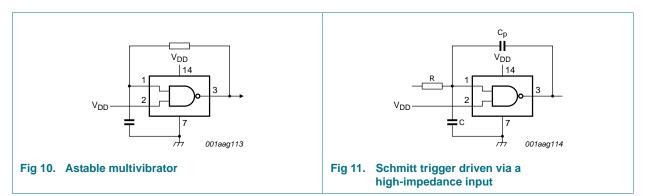
Fig 8. Typical drain current as a function of input



## 14. Application information

Some examples of applications for the HEF4093B-Q100 are:

- · Wave and pulse shapers
- Astable multivibrators
- Monostable multivibrators



If a Schmitt trigger is driven via a high-impedance (R > 1 k $\Omega$ ), then it is necessary to incorporate a capacitor C with a value of  $\frac{C}{C_P} > \frac{V_{DD} - V_{SS}}{V_H}$ ; otherwise oscillation can occur on the edges of a pulse.

 $\ensuremath{C_p}$  is the external parasitic capacitance between inputs and output; the value depends on the circuit board layout.

**Remark:** The two inputs may be connected together, but this will result in a larger through-current at the moment of switching.

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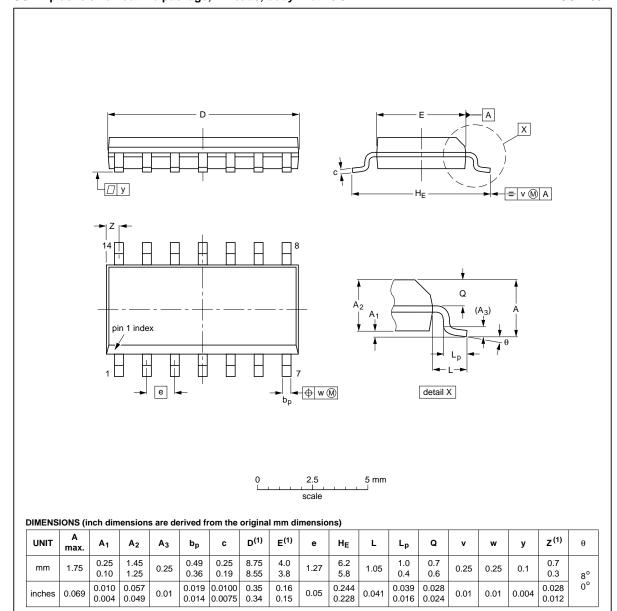
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## 15. Package outline

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT108-1	076E06	MS-012				<del>99-12-27</del> 03-02-19	

Fig 12. Package outline SOT108-1 (SO14)

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**Product data sheet** 

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### 16. Abbreviations

#### Table 12. Abbreviations

Acronym	Description
HBM	Human Body Model
ESD	ElectroStatic Discharge
MM	Machine Model
MIL	Military

## 17. Revision history

#### Table 13. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
HEF4093B_Q100 v.1	20120712	Product specification	-	-

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#### 18.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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